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Recent Machine Learning Applications to Internet of Things (IoT)

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Deadline for manuscript submissions:

closed (30 June 2020)

Message from the Guest Editors

General topics covered in this Special Issue include but are not limited to the following methodologies and IoT applications:

- Methodologies:
 - Soft computing (e.g., fuzzy logic, rough sets);
 - Neural networks;
 - Neuro-fuzzy systems;
 - Deep learning;
 - Evolutionary and bio-inspired algorithms;
- Applications:
 - Machine learning and computational intelligence-aided IoT;
 - Intelligent middleware solutions IoT;
 - Brain-computer interface and IoT;
 - IoT and cloud computing;
 - Semantic web of things;
 - Social network IoT;
 - o Internet of vehicles;
 - Context awareness;
 - Security and IoT.

Welcome to contribute!











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Message from the Editor-in-Chief

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